 earch Notes		

	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/673,366	CHANG ET AL.
	Examiner	Art Unit
-	James R. Scott K. Lee	2832

SEARCHED			
Class	Subclass	Date	Examiner
439	586-603 620 842 904-906	4/18/2005	JRS
SEARCH	updated	10/15/05	KL
			-

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	-		

	CH NOTES EARCH STRATEGY)
	DATE	EXMR
EAST	4/18/2005	JRS
PLUS	4/18/2005	JRS